

## Aluminum nitride – From amorphous to highly oriented hexagonal thin films

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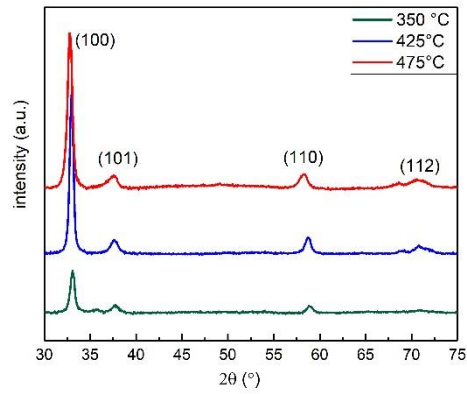


Figure 1, XRD diffractograms of thermal ALD AlN grown from TMA and NH<sub>3</sub>.

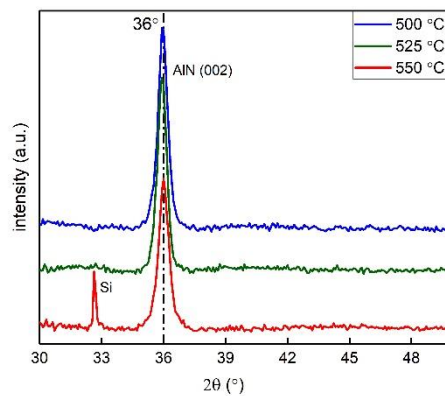


Figure 2, XRD diffractograms of thermal ALD AlN grown from AlCl<sub>3</sub> and NH<sub>3</sub>.